Infineon Technologies - MB96F625ABPMC-GSE2 Datasheet

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	F²MC-16FX
Core Size	16-Bit
Speed	32MHz
Connectivity	I²C, LINbus, SCI, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	52
Program Memory Size	160KB (160K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	10K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 21x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (12x12)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/mb96f625abpmc-gse2

- A/D converter
  - SAR-type
  - 8/10-bit resolution
  - Signals interrupt on conversion end, single conversion mode, continuous conversion mode, stop conversion mode, activation by software, external trigger, reload timers and PPGs
  - Range Comparator Function
- Source Clock Timers

  Three independent clock timers (23-bit RC clock timer, 23-bit Main clock timer, 17-bit Sub clock timer)
- Hardware Watchdog Timer
  - Hardware watchdog timer is active after reset
  - Window function of Watchdog Timer is used to select the lower window limit of the watchdog interval
- Reload Timers
  - 16-bit wide
  - Prescaler with $1/2^1$, $1/2^2$, $1/2^3$, $1/2^4$, $1/2^5$, $1/2^6$ of peripheral clock frequency
  - Event count function
- Free-Running Timers
  - Signals an interrupt on overflow, supports timer clear upon match with Output Compare (0, 4)
  - Prescaler with 1, $1/2^1$, $1/2^2$, $1/2^3$, $1/2^4$, $1/2^5$, $1/2^6$, $1/2^7$, $1/2^8$ of peripheral clock frequency
- Input Capture Units
  - 16-bit wide
  - Signals an interrupt upon external event
  - Rising edge, Falling edge or Both (rising & falling) edges sensitive
- Output Compare Units
  - 16-bit wide
  - Signals an interrupt when a match with Free-running Timer occurs
  - A pair of compare registers can be used to generate an output signal
- Programmable Pulse Generator
  - 16-bit down counter, cycle and duty setting registers
  - Can be used as 2 × 8-bit PPG
  - Interrupt at trigger, counter borrow and/or duty match
  - PWM operation and one-shot operation
  - Internal prescaler allows 1, 1/4, 1/16, 1/64 of peripheral clock as counter clock or of selected Reload timer underflow as clock input
  - Can be triggered by software or reload timer
  - Can trigger ADC conversion
  - Timing point capture
- Quadrature Position/Revolution Counter (QPRC)
  - Up/down count mode, Phase difference count mode, Count mode with direction
  - 16-bit position counter
  - 16-bit revolution counter
  - Two 16-bit compare registers with interrupt
  - Detection edge of the three external event input pins AIN, BIN and ZIN is configurable
- Real Time Clock
  - Operational on main oscillation (4MHz), sub oscillation (32kHz) or RC oscillation (100kHz/2MHz)
  - Capable to correct oscillation deviation of Sub clock or RC oscillator clock (clock calibration)
  - Read/write accessible second/minute/hour registers
  - Can signal interrupts every half second/second/minute/hour/day
  - Internal clock divider and prescaler provide exact 1s clock
- External Interrupts
  - Edge or Level sensitive
  - Interrupt mask bit per channel
  - Each available CAN channel RX has an external interrupt for wake-up
  - Selected USART channels SIN have an external interrupt for wake-up
- Non Maskable Interrupt
  - Disabled after reset, can be enabled by Boot-ROM depending on ROM configuration block
  - Once enabled, can not be disabled other than by reset
  - High or Low level sensitive
  - Pin shared with external interrupt 0
- I/O Ports
  - Most of the external pins can be used as general purpose I/O
  - All push-pull outputs (except when used as I^2C SDA/SCL line)
  - Bit-wise programmable as input/output or peripheral signal
  - Bit-wise programmable input enable
  - One input level per GPIO-pin (either Automotive or CMOS hysteresis)
  - Bit-wise programmable pull-up resistor
- Built-in On Chip Debugger (OCD)
  - One-wire debug tool interface
  - Break function:
    - Hardware break: 6 points (shared with code event)
    - Software break: 4096 points
  - Event function
    - Code event: 6 points (shared with hardware break)
    - Data event: 6 points
    - Event sequencer: 2 levels + reset
  - Execution time measurement function
  - Trace function: 42 branches
  - Security function
- Flash Memory
  - Dual operation flash allowing reading of one Flash bank while programming or erasing the other bank
  - Command sequencer for automatic execution of programming algorithm and for supporting DMA for programming of the Flash Memory
  - Supports automatic programming, Embedded Algorithm
  - Write/Erase/Erase-Suspend/Resume commands
  - A flag indicating completion of the automatic algorithm
  - Erase can be performed on each sector individually
  - Sector protection
  - Flash Security feature to protect the content of the Flash
  - Low voltage detection during Flash erase or write

1. Product Lineup

Features			MB96620	Remark
Product Type			Flash Memory Product	
Subclock			Subclock can be set by software	
Dual Operation Flash Memory		RAM	-	
32.5KB + 32KB		4KB	MB96F622R, MB96F622A	Product Options R: MCU with CAN A: MCU without CAN
64.5KB + 32KB		10KB	MB96F623R, MB96F623A	
128.5KB + 32KB		10KB	MB96F625R, MB96F625A	
Package			LQFP-64 FPT-64P-M23/M24	
DMA			2ch	
USART			3ch	LIN-USART 2/7/8
	with automatic LIN-Header transmission/reception		Yes (only 1ch)	LIN-USART 2
	with 16 byte RX- and TX-FIFO		No	
I^2C			1ch	I^2C 0
8/10-bit A/D Converter			21ch	AN 0 to 14/24/25/28 to 31
	with Data Buffer		No	
	with Range Comparator		Yes	
	with Scan Disable		No	
	with ADC Pulse Detection		No	
16-bit Reload Timer (RLT)			3ch	RLT 1/3/6
16-bit Free-Running Timer (FRT)			4ch	FRT 0 to 3 FRT 2/3 does not have external clock input pin
16-bit Input Capture Unit (ICU)			8ch (2 channels for LIN-USART)	ICU 0/1/4 to 7/9/10 (ICU 9/10 for LIN-USART)
16-bit Output Compare Unit (OCU)			6ch	OCU 0/1/4 to 7
8/16-bit Programmable Pulse Generator (PPG)			8ch (16-bit) / 16ch (8-bit)	PPG 0/1/3/4/6/7/12/14
	with Timing point capture		Yes	
	with Start delay		No	
	with Ramp		No	
Quadrature Position/Revolution Counter (QPRC)			2ch	QPRC 0/1
CAN Interface			1ch	CAN 2 32 Message Buffers
External Interrupts (INT)			13ch	INT 0/2/3/4/7 to 15
Non-Maskable Interrupt (NMI)			1ch	
Real Time Clock (RTC)			1ch	
I/O Ports			50 (Dual clock mode) 52 (Single clock mode)	
Clock Calibration Unit (CAL)			1ch	
Clock Output Function			2ch	
Low Voltage Detection Function			Yes	Low voltage detection function can be disabled by software
Hardware Watchdog Timer			Yes	
On-chip RC-oscillator			Yes	
On-chip Debugger			Yes	

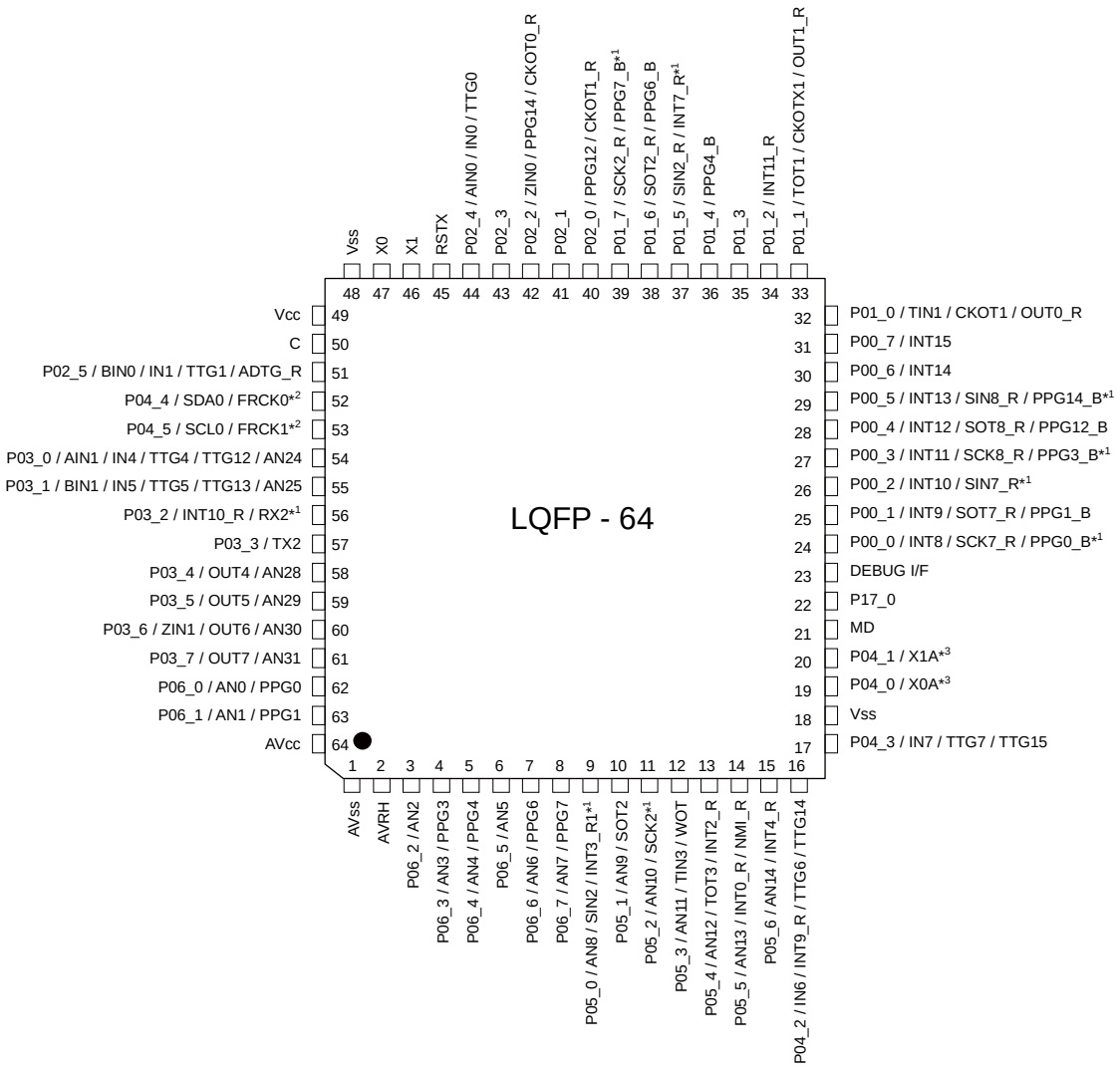
Note:

All signals of the peripheral function in each product cannot be allocated by limiting the pins of package.

It is necessary to use the port relocate function of the general I/O port according to your function use.

3. Pin Assignment

(Top view)



(FPT-64P-M23/M24)

*1: CMOS input level only

*2: CMOS input level only for I^2C

*3: Please set ROM Configuration Block (RCB) to use the subclock.

Other than those above, general-purpose pins have only Automotive input level.

9. User ROM Memory Map For Flash Devices

CPU mode address	Flash memory mode address	MB96F622 Flash size 32.5KB + 32KB	MB96F623 Flash size 64.5KB + 32KB	MB96F625 Flash size 128.5KB + 32KB	
$FF:FFFF_H$ $FF:8000_H$	$3F:FFFF_H$ $3F:8000_H$	SA39 - 32KB	SA39 - 64KB	SA39 - 64KB	Bank A of Flash A
$FF:7FFF_H$ $FF:0000_H$	$3F:7FFF_H$ $3F:0000_H$	Reserved			
$FE:FFFF_H$ $FE:0000_H$	$3E:FFFF_H$ $3E:0000_H$		Reserved	SA38 - 64KB	
$FD:FFFF_H$ $DF:A000_H$				Reserved	
$DF:9FFF_H$ $DF:8000_H$	$1F:9FFF_H$ $1F:8000_H$	SA4 - 8KB	SA4 - 8KB	SA4 - 8KB	Bank B of Flash A
$DF:7FFF_H$ $DF:6000_H$	$1F:7FFF_H$ $1F:6000_H$	SA3 - 8KB	SA3 - 8KB	SA3 - 8KB	
$DF:5FFF_H$ $DF:4000_H$	$1F:5FFF_H$ $1F:4000_H$	SA2 - 8KB	SA2 - 8KB	SA2 - 8KB	
$DF:3FFF_H$ $DF:2000_H$	$1F:3FFF_H$ $1F:2000_H$	SA1 - 8KB	SA1 - 8KB	SA1 - 8KB	
$DF:1FFF_H$ $DF:0000_H$	$1F:1FFF_H$ $1F:0000_H$	SAS - 512B*	SAS - 512B*	SAS - 512B*	Bank A of Flash A
$DE:FFFF_H$ $DE:0000_H$		Reserved	Reserved	Reserved	

*: Physical address area of SAS-512B is from $DF:0000_H$ to $DF:01FF_H$.
Others (from $DF:0200_H$ to $DF:1FFF_H$) is mirror area of SAS-512B.
Sector SAS contains the ROM configuration block RCBA at CPU address $DF:0000_H$ -$DF:01FF_H$.
SAS can not be used for E^2PROM emulation.

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
40	$35C_H$	-	-	40	Reserved
41	358H	PPG3	Yes	41	Programmable Pulse Generator 3
42	354H	PPG4	Yes	42	Programmable Pulse Generator 4
43	350H	-	-	43	Reserved
44	34CH	PPG6	Yes	44	Programmable Pulse Generator 6
45	348H	PPG7	Yes	45	Programmable Pulse Generator 7
46	344H	-	-	46	Reserved
47	340H	-	-	47	Reserved
48	33CH	-	-	48	Reserved
49	338H	-	-	49	Reserved
50	334H	PPG12	Yes	50	Programmable Pulse Generator 12
51	330H	-	-	51	Reserved
52	32CH	PPG14	Yes	52	Programmable Pulse Generator 14
53	328H	-	-	53	Reserved
54	324H	-	-	54	Reserved
55	320H	-	-	55	Reserved
56	31CH	-	-	56	Reserved
57	318H	-	-	57	Reserved
58	314H	-	-	58	Reserved
59	310H	RLT1	Yes	59	Reload Timer 1
60	30CH	-	-	60	Reserved
61	308H	RLT3	Yes	61	Reload Timer 3
62	304H	-	-	62	Reserved
63	300H	-	-	63	Reserved
64	2FCH	RLT6	Yes	64	Reload Timer 6
65	2F8H	ICU0	Yes	65	Input Capture Unit 0
66	2F4H	ICU1	Yes	66	Input Capture Unit 1
67	2F0H	-	-	67	Reserved
68	2ECH	-	-	68	Reserved
69	2E8H	ICU4	Yes	69	Input Capture Unit 4
70	2E4H	ICU5	Yes	70	Input Capture Unit 5
71	2E0H	ICU6	Yes	71	Input Capture Unit 6
72	2DCH	ICU7	Yes	72	Input Capture Unit 7
73	2D8H	-	-	73	Reserved
74	2D4H	ICU9	Yes	74	Input Capture Unit 9
75	2D0H	ICU10	Yes	75	Input Capture Unit 10
76	2CCH	-	-	76	Reserved
77	2C8H	OCU0	Yes	77	Output Compare Unit 0
78	2C4H	OCU1	Yes	78	Output Compare Unit 1
79	2C0H	-	-	79	Reserved
80	2BCH	-	-	80	Reserved

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
81	$2B8_H$	OCU4	Yes	81	Output Compare Unit 4
82	$2B4_H$	OCU5	Yes	82	Output Compare Unit 5
83	$2B0_H$	OCU6	Yes	83	Output Compare Unit 6
84	$2AC_H$	OCU7	Yes	84	Output Compare Unit 7
85	$2A8_H$	-	-	85	Reserved
86	$2A4_H$	-	-	86	Reserved
87	$2A0_H$	-	-	87	Reserved
88	$29C_H$	-	-	88	Reserved
89	298_H	FRT0	Yes	89	Free-Running Timer 0
90	294_H	FRT1	Yes	90	Free-Running Timer 1
91	290_H	FRT2	Yes	91	Free-Running Timer 2
92	$28C_H$	FRT3	Yes	92	Free-Running Timer 3
93	288_H	RTC0	No	93	Real Time Clock
94	284_H	CAL0	No	94	Clock Calibration Unit
95	280_H	-	-	95	Reserved
96	$27C_H$	IIC0	Yes	96	I^2C interface 0
97	278_H	-	-	97	Reserved
98	274_H	ADC0	Yes	98	A/D Converter 0
99	270_H	-	-	99	Reserved
100	$26C_H$	-	-	100	Reserved
101	268_H	-	-	101	Reserved
102	264_H	-	-	102	Reserved
103	260_H	-	-	103	Reserved
104	$25C_H$	-	-	104	Reserved
105	258_H	LINR2	Yes	105	LIN USART 2 RX
106	254_H	LINT2	Yes	106	LIN USART 2 TX
107	250_H	-	-	107	Reserved
108	$24C_H$	-	-	108	Reserved
109	248_H	-	-	109	Reserved
110	244_H	-	-	110	Reserved
111	240_H	-	-	111	Reserved
112	$23C_H$	-	-	112	Reserved
113	238_H	-	-	113	Reserved
114	234_H	-	-	114	Reserved
115	230_H	LINR7	Yes	115	LIN USART 7 RX
116	$22C_H$	LINT7	Yes	116	LIN USART 7 TX
117	228_H	LINR8	Yes	117	LIN USART 8 RX
118	224_H	LINT8	Yes	118	LIN USART 8 TX
119	220_H	-	-	119	Reserved
120	$21C_H$	-	-	120	Reserved
121	218_H	-	-	121	Reserved
122	214_H	-	-	122	Reserved

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
123	210_H	-	-	123	Reserved
124	$20C_H$	-	-	124	Reserved
125	208_H	-	-	125	Reserved
126	204_H	-	-	126	Reserved
127	200_H	-	-	127	Reserved
128	$1FC_H$	-	-	128	Reserved
129	$1F8_H$	-	-	129	Reserved
130	$1F4_H$	-	-	130	Reserved
131	$1F0_H$	-	-	131	Reserved
132	$1EC_H$	-	-	132	Reserved
133	$1E8_H$	FLASHA	Yes	133	Flash memory A interrupt
134	$1E4_H$	-	-	134	Reserved
135	$1E0_H$	-	-	135	Reserved
136	$1DC_H$	-	-	136	Reserved
137	$1D8_H$	QPRC0	Yes	137	Quad Position/Revolution counter 0
138	$1D4_H$	QPRC1	Yes	138	Quad Position/Revolution counter 1
139	$1D0_H$	ADCRC0	No	139	A/D Converter 0 - Range Comparator
140	$1CC_H$	-	-	140	Reserved
141	$1C8_H$	-	-	141	Reserved
142	$1C4_H$	-	-	142	Reserved
143	$1C0_H$	-	-	143	Reserved

12. Handling Precautions

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

12.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

■Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

■Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

■Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

1. Preventing Over-Voltage and Over-Current Conditions

   Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.
2. Protection of Output Pins

   Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device.
   Therefore, avoid this type of connection.
3. Handling of Unused Input Pins

   Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

■Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

1. Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
2. Be sure that abnormal current flows do not occur during the power-on sequence.

■Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

■Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

■Precautions Related to Usage of Devices
Cypress semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION: Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

12.2 Precautions for Package Mounting
Package mounting may be either lead insertion type or surface mount type. In either case, for heat resistance during soldering, you should only mount under Cypress's recommended conditions. For detailed information about mount conditions, contact your sales representative.

■Lead Insertion Type
Mounting of lead insertion type packages onto printed circuit boards may be done by two methods: direct soldering on the board, or mounting by using a socket.

Direct mounting onto boards normally involves processes for inserting leads into through-holes on the board and using the flow soldering (wave soldering) method of applying liquid solder. In this case, the soldering process usually causes leads to be subjected to thermal stress in excess of the absolute ratings for storage temperature. Mounting processes should conform to Cypress recommended mounting conditions.

If socket mounting is used, differences in surface treatment of the socket contacts and IC lead surfaces can lead to contact deterioration after long periods. For this reason it is recommended that the surface treatment of socket contacts and IC leads be verified before mounting.

■Surface Mount Type
Surface mount packaging has longer and thinner leads than lead-insertion packaging, and therefore leads are more easily deformed or bent. The use of packages with higher pin counts and narrower pin pitch results in increased susceptibility to open connections caused by deformed pins, or shorting due to solder bridges.

You must use appropriate mounting techniques. Cypress recommends the solder reflow method, and has established a ranking of mounting conditions for each product. Users are advised to mount packages in accordance with Cypress ranking of recommended conditions.

■Lead-Free Packaging
CAUTION: When ball grid array (BGA) packages with Sn-Ag-Cu balls are mounted using Sn-Pb eutectic soldering, junction strength may be reduced under some conditions of use.

■Storage of Semiconductor Devices
Because plastic chip packages are formed from plastic resins, exposure to natural environmental conditions will cause absorption of moisture. During mounting, the application of heat to a package that has absorbed moisture can cause surfaces to peel, reducing moisture resistance and causing packages to crack. To prevent, do the following:

1. Avoid exposure to rapid temperature changes, which cause moisture to condense inside the product. Store products in locations where temperature changes are slight.
2. Use dry boxes for product storage. Products should be stored below 70% relative humidity, and at temperatures between 5°C and 30°C.
   When you open Dry Package that recommends humidity 40% to 70% relative humidity.
3. When necessary, Cypress packages semiconductor devices in highly moisture-resistant aluminum laminate bags, with a silica gel desiccant. Devices should be sealed in their aluminum laminate bags for storage.
4. Avoid storing packages where they are exposed to corrosive gases or high levels of dust.

■Baking
Packages that have absorbed moisture may be de-moisturized by baking (heat drying). Follow the Cypress recommended conditions for baking.

Condition: 125°C/24 h

14. Electrical Characteristics

14.1 Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating		Unit	Remarks
			Min	Max		
Power supply voltage*1	V_{CC}	-	V_{SS} - 0.3	V_{SS} + 6.0	V	
Analog power supply voltage*1	AV_{CC}	-	V_{SS} - 0.3	V_{SS} + 6.0	V	$V_{CC} = AV_{CC}$*2
Analog reference voltage*1	AVRH	-	V_{SS} - 0.3	V_{SS} + 6.0	V	$AV_{CC} \geq AVRH$, $AVRH \geq AV_{SS}$
Input voltage*1	V_I	-	V_{SS} - 0.3	V_{SS} + 6.0	V	$V_I \leq V_{CC}$ + 0.3V*3
Output voltage*1	V_O	-	V_{SS} - 0.3	V_{SS} + 6.0	V	$V_O \leq V_{CC}$ + 0.3V*3
Maximum Clamp Current	I_{CLAMP}	-	-4.0	+4.0	mA	Applicable to general purpose I/O pins *4
Total Maximum Clamp Current	$\Sigma\lvert I_{CLAMP}\rvert$	-	-	17	mA	Applicable to general purpose I/O pins *4
"L" level maximum output current	I_{OL}	-	-	15	mA	
"L" level average output current	I_{OLAV}	-	-	4	mA	
"L" level maximum overall output current	ΣI_{OL}	-	-	42	mA	
"L" level average overall output current	ΣI_{OLAV}	-	-	21	mA	
"H" level maximum output current	I_{OH}	-	-	-15	mA	
"H" level average output current	I_{OHAV}	-	-	-4	mA	
"H" level maximum overall output current	ΣI_{OH}	-	-	-42	mA	
"H" level average overall output current	ΣI_{OHAV}	-	-	-21	mA	
Power consumption*5	P_D	T_A= +125°C	-	352*6	mW	
Operating ambient temperature	T_A	-	-40	+125*7	°C	
Storage temperature	T_{STG}	-	-55	+150	°C	

*1: This parameter is based on $V_{SS} = AV_{SS} = 0V$.

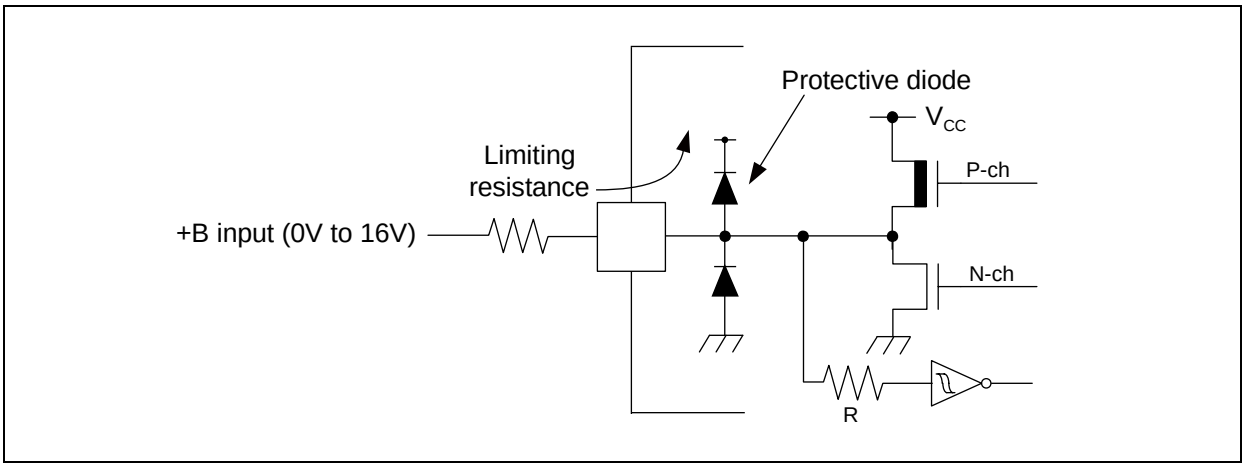
*2: AV_{CC} and V_{CC} must be set to the same voltage. It is required that AV_{CC} does not exceed V_{CC} and that the voltage at the analog inputs does not exceed AV_{CC} when the power is switched on.

*3: V_I and V_O should not exceed V_{CC} + 0.3V. V_I should also not exceed the specified ratings. However if the maximum current to/from an input is limited by some means with external components, the I_{CLAMP} rating supersedes the V_I rating. Input/Output voltages of standard ports depend on V_{CC}.

*4: Applicable to all general purpose I/O pins (Pnn_m).

- Use within recommended operating conditions.
- Use at DC voltage (current).
- The +B signal should always be applied a limiting resistance placed between the +B signal and the microcontroller.
- The value of the limiting resistance should be set so that when the +B signal is applied the input current to the microcontroller pin does not exceed rated values, either instantaneously or for prolonged periods.
- Note that when the microcontroller drive current is low, such as in the power saving modes, the +B input potential may pass through the protective diode and increase the potential at the V_{CC} pin, and this may affect other devices.
- Note that if a +B signal is input when the microcontroller power supply is off (not fixed at 0V), the power supply is provided from the pins, so that incomplete operation may result.
- Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset.

- The DEBUG I/F pin has only a protective diode against V_{SS}. Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.
- Sample recommended circuits:



*5: The maximum permitted power dissipation depends on the ambient temperature, the air flow velocity and the thermal conductance of the package on the PCB.
The actual power dissipation depends on the customer application and can be calculated as follows:
$P_D = P_{IO} + P_{INT}$
$P_{IO} = \Sigma (V_{OL} \times I_{OL} + V_{OH} \times I_{OH})$ (I/O load power dissipation, sum is performed on all I/O ports)
$P_{INT} = V_{CC} \times (I_{CC} + I_A)$ (internal power dissipation)
I_{CC} is the total core current consumption into V_{CC} as described in the “DC characteristics” and depends on the selected operation mode and clock frequency and the usage of functions like Flash programming.
I_A is the analog current consumption into AV_{CC}.

*6: Worst case value for a package mounted on single layer PCB at specified T_A without air flow.

*7: Write/erase to a large sector in flash memory is warranted with TA ≤ + 105°C.

WARNING
Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Power supply current in Timer modes[*2]	I_{CCTPLL}	Vcc	PLL Timer mode with CLKPLL = 32MHz (CLKRC and CLKSC stopped)	-	1800	2245	µA	T_A = +25°C
				-	-	3165	µA	T_A = +105°C
				-	-	3975	µA	T_A = +125°C
	$I_{CCTMAIN}$		Main Timer mode with CLKMC = 4MHz, SMCR:LPMSS = 0 (CLKPLL, CLKRC and CLKSC stopped)	-	285	325	µA	T_A = +25°C
				-	-	1085	µA	T_A = +105°C
				-	-	1930	µA	T_A = +125°C
	I_{CCTRCH}		RC Timer mode with CLKRC = 2MHz, SMCR:LPMSS = 0 (CLKPLL, CLKMC and CLKSC stopped)	-	160	210	µA	T_A = +25°C
				-	-	1025	µA	T_A = +105°C
				-	-	1840	µA	T_A = +125°C
	I_{CCTRCL}		RC Timer mode with CLKRC = 100kHz (CLKPLL, CLKMC and CLKSC stopped)	-	35	75	µA	T_A = +25°C
				-	-	855	µA	T_A = +105°C
				-	-	1640	µA	T_A = +125°C
	I_{CCTSUB}		Sub Timer mode with CLKSC = 32kHz (CLKMC, CLKPLL and CLKRC stopped)	-	25	65	µA	T_A = +25°C
				-	-	830	µA	T_A = +105°C
				-	-	1620	µA	T_A = +125°C

14.3.2 Pin Characteristics

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

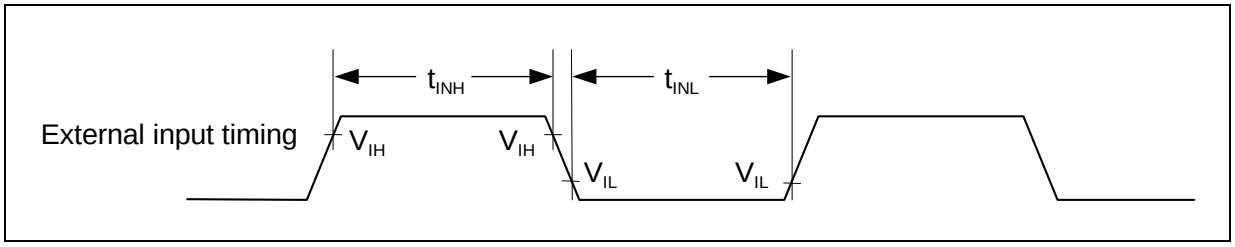
Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
"H" level input voltage	V_{IH}	Port inputs Pnn_m	-	V_{CC} × 0.7	-	V_{CC} + 0.3	V	CMOS Hysteresis input
			-	V_{CC} × 0.8	-	V_{CC} + 0.3	V	AUTOMOTIVE Hysteresis input
	V_{IHX0S}	X0	External clock in "Fast Clock Input mode"	VD × 0.8	-	VD	V	VD=1.8V±0.15V
	V_{IHX0AS}	X0A	External clock in "Oscillation mode"	V_{CC} × 0.8	-	V_{CC} + 0.3	V	
	V_{IHR}	RSTX	-	V_{CC} × 0.8	-	V_{CC} + 0.3	V	CMOS Hysteresis input
	V_{IHM}	MD	-	V_{CC} - 0.3	-	V_{CC} + 0.3	V	CMOS Hysteresis input
	V_{IHD}	DEBUG I/F	-	2.0	-	V_{CC} + 0.3	V	TTL Input
"L" level input voltage	V_{IL}	Port inputs Pnn_m	-	V_{SS} - 0.3	-	V_{CC} × 0.3	V	CMOS Hysteresis input
			-	V_{SS} - 0.3	-	V_{CC} × 0.5	V	AUTOMOTIVE Hysteresis input
	V_{ILX0S}	X0	External clock in "Fast Clock Input mode"	V_{SS}	-	VD × 0.2	V	VD=1.8V±0.15V
	V_{ILX0AS}	X0A	External clock in "Oscillation mode"	V_{SS} - 0.3	-	V_{CC} × 0.2	V	
	V_{ILR}	RSTX	-	V_{SS} - 0.3	-	V_{CC} × 0.2	V	CMOS Hysteresis input
	V_{ILM}	MD	-	V_{SS} - 0.3	-	V_{SS} + 0.3	V	CMOS Hysteresis input
	V_{ILD}	DEBUG I/F	-	V_{SS} - 0.3	-	0.8	V	TTL Input

14.4.9 External Input Timing

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Pin name	Value		Unit	Remarks
			Min	Max		
Input pulse width	t_{INH}, t_{INL}	Pnn_m	$2t_{CLKP1}$ +200 (t_{CLKP1}= $1/f_{CLKP1}$)*	-	ns	General Purpose I/O
		ADTG_R				A/D Converter trigger input
		TINn				Reload Timer
		TTGn				PPG trigger input
		FRCKn				Free-Running Timer input clock
		INn				Input Capture
		AINn, BINn, ZINn				Quadrature Position/Revolution Counter
		INTn, INTn_R, INTn_R1	200	-	ns	External Interrupt
		NMI_R				Non-Maskable Interrupt

*: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time except stop when in stop mode.



14.4.10 I^2C Timing

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Conditions	Typical mode		High-speed mode*4		Unit
			Min	Max	Min	Max	
SCL clock frequency	f_{SCL}	C_L = 50pF, R = (Vp/I_{OL})*1	0	100	0	400	kHz
(Repeated) START condition hold time SDA ↓ → SCL ↓	t_{HDSTA}		4.0	-	0.6	-	µs
SCL clock "L" width	t_{LOW}		4.7	-	1.3	-	µs
SCL clock "H" width	t_{HIGH}		4.0	-	0.6	-	µs
(Repeated) START condition setup time SCL ↑ → SDA ↓	t_{SUSTA}		4.7	-	0.6	-	µs
Data hold time SCL ↓ → SDA ↓ ↑	t_{HDDAT}		0	3.45*2	0	0.9*3	µs
Data setup time SDA ↓ ↑ → SCL ↑	t_{SUDAT}		250	-	100	-	ns
STOP condition setup time SCL ↑ → SDA ↑	t_{SUSTO}		4.0	-	0.6	-	µs
Bus free time between "STOP condition" and "START condition"	t_{BUS}		4.7	-	1.3	-	µs
Pulse width of spikes which will be suppressed by input noise filter	t_{SP}	-	0	(1-1.5) × t_{CLKP1}*5	0	(1-1.5) × t_{CLKP1}*5	ns

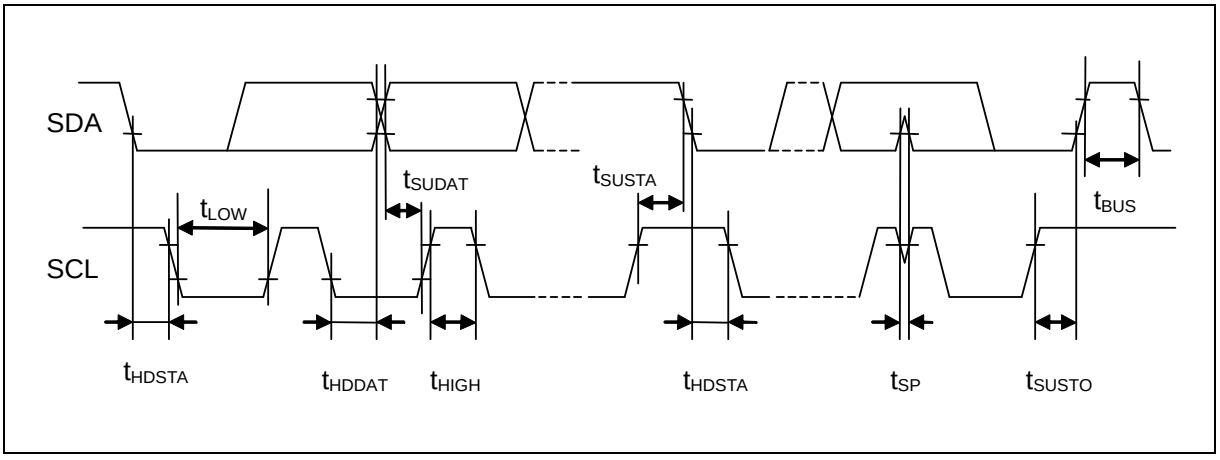
*1: R and C_L represent the pull-up resistance and load capacitance of the SCL and SDA lines, respectively. Vp indicates the power supply voltage of the pull-up resistance and I_{OL} indicates V_{OL} guaranteed current.

*2: The maximum t_{HDDAT} only has to be met if the device does not extend the "L" width (t_{LOW}) of the SCL signal.

*3: A high-speed mode I^2C bus device can be used on a standard mode I^2C bus system as long as the device satisfies the requirement of "t_{SUDAT} ≥ 250ns".

*4: For use at over 100kHz, set the peripheral clock1 (CLKP1) to at least 6MHz.

*5: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time.



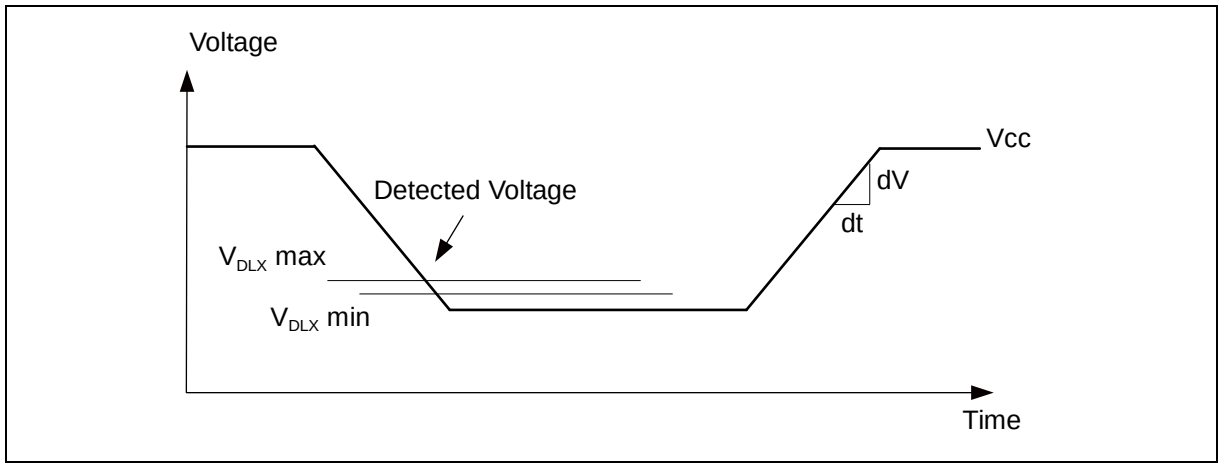
14.6 Low Voltage Detection Function Characteristics

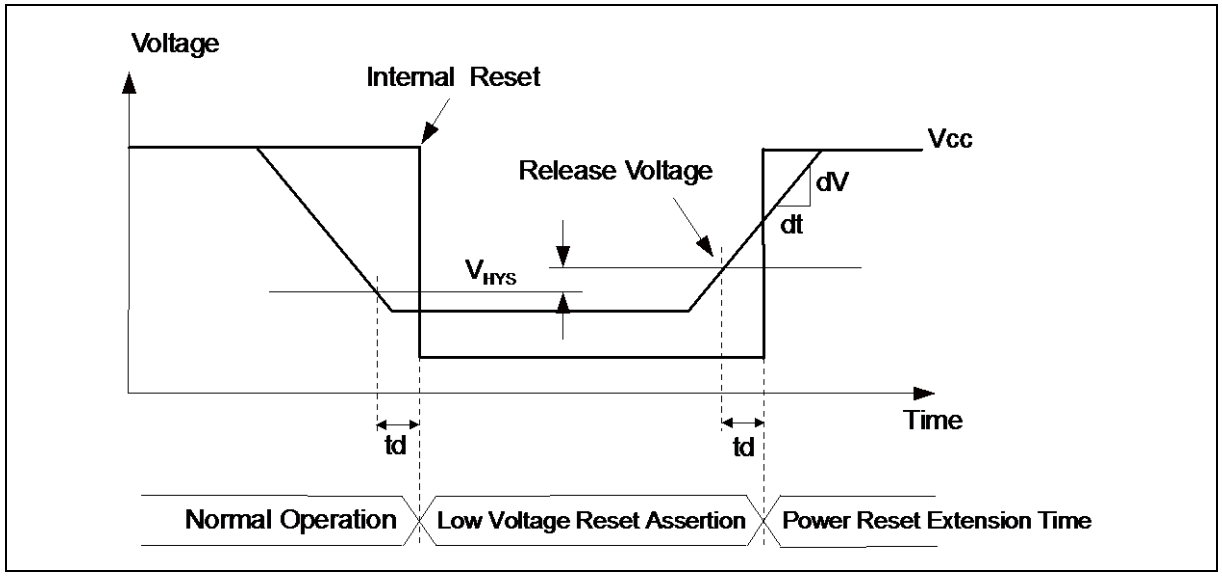
(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

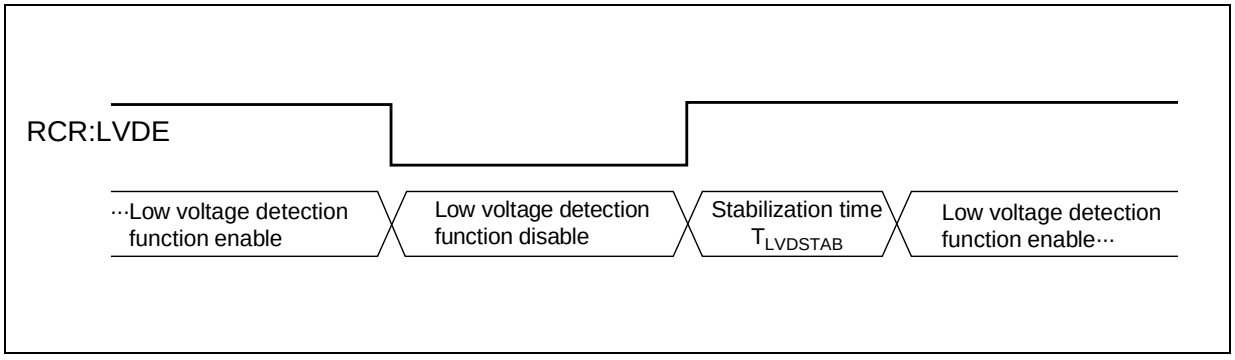
Parameter	Symbol	Conditions	Value			Unit
			Min	Typ	Max	
Detected voltage[*1]	V_{DL0}	CILCR:LVL = 0000_B	2.70	2.90	3.10	V
	V_{DL1}	CILCR:LVL = 0001_B	2.79	3.00	3.21	V
	V_{DL2}	CILCR:LVL = 0010_B	2.98	3.20	3.42	V
	V_{DL3}	CILCR:LVL = 0011_B	3.26	3.50	3.74	V
	V_{DL4}	CILCR:LVL = 0100_B	3.45	3.70	3.95	V
	V_{DL5}	CILCR:LVL = 0111_B	3.73	4.00	4.27	V
	V_{DL6}	CILCR:LVL = 1001_B	3.91	4.20	4.49	V
Power supply voltage change rate[*2]	dV/dt	-	- 0.004	-	+ 0.004	V/µs
Hysteresis width	V_{HYS}	CILCR:LVHYS=0	-	-	50	mV
		CILCR:LVHYS=1	80	100	120	mV
Stabilization time	$T_{LVDSTAB}$	-	-	-	75	µs
Detection delay time	t_d	-	-	-	30	µs

[*1]: If the power supply voltage fluctuates within the time less than the detection delay time (t_d), there is a possibility that the low voltage detection will occur or stop after the power supply voltage passes the detection range.

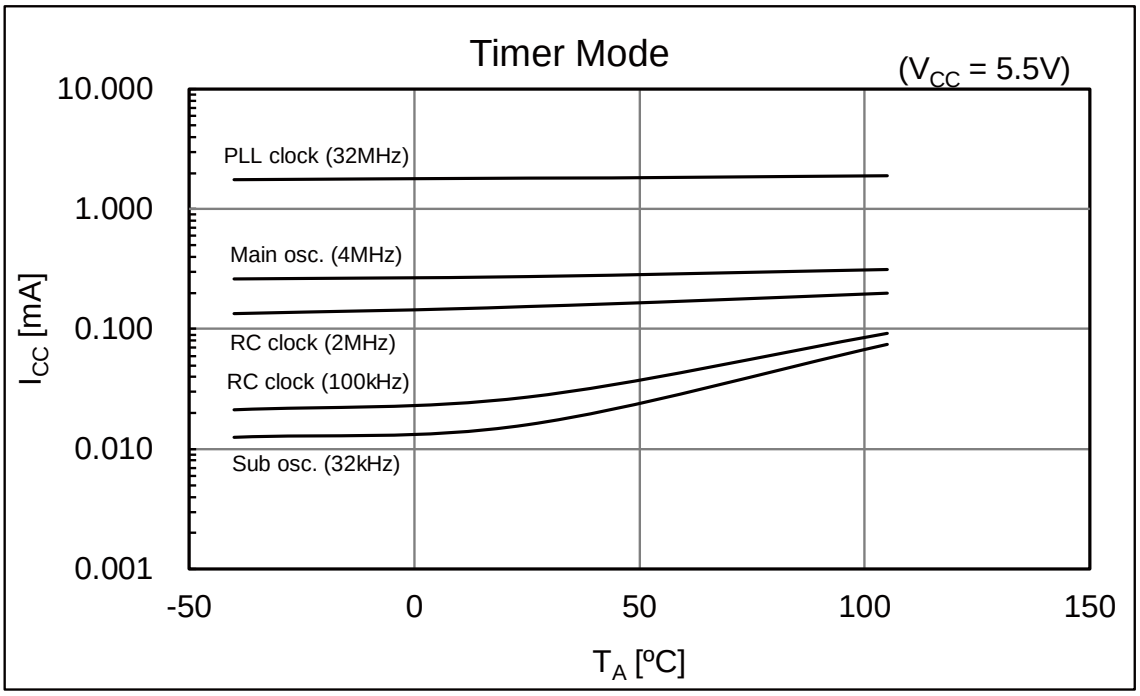
[*2]: In order to perform the low voltage detection at the detection voltage (V_{DLX}), be sure to suppress fluctuation of the power supply voltage within the limits of the change ration of power supply voltage.

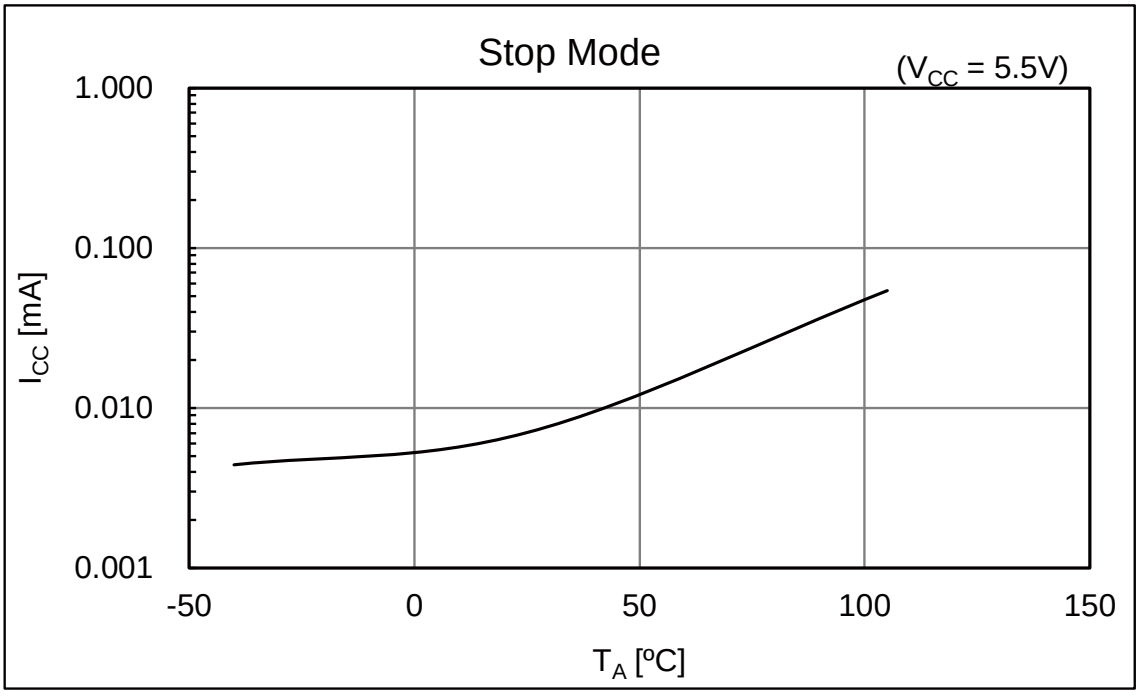

Voltage
Vcc
Detected Voltage
dV
dt
V_{DLX} max
V_{DLX} min
Time


Voltage
Internal Reset
Vcc
Release Voltage
dV
dt
V_{HYS}
Time
td
td
Normal Operation
Low Voltage Reset Assertion
Power Reset Extension Time


RCR:LVDE
···Low voltage detection function enable
Low voltage detection function disable
Stabilization time $T_{LVDSTAB}$
Low voltage detection function enable···

■MB96F625


Timer Mode
(V_{CC} = 5.5V)
10.000
1.000
0.100
0.010
0.001
I_{CC} [mA]
PLL clock (32MHz)
Main osc. (4MHz)
RC clock (2MHz)
RC clock (100kHz)
Sub osc. (32kHz)
-50
0
50
100
150
T_A [ºC]


Stop Mode
(V_{CC} = 5.5V)
1.000
0.100
0.010
0.001
I_{CC} [mA]
-50
0
50
100
150
T_A [ºC]

16. Ordering Information

MCU with CAN controller

Part number	Flash memory	Package*
MB96F622RBPMC-GSE1	Flash A (64.5KB)	64-pin plastic LQFP (FPT-64P-M23)
MB96F622RBPMC-GSE2		
MB96F622RBPMC-GTE1		
MB96F622RBPMC1-GSE1		64-pin plastic LQFP (FPT-64P-M24)
MB96F622RBPMC1-GSE2		
MB96F622RBPMC1-GTE1		
MB96F623RBPMC-GSE1	Flash A (96.5KB)	64-pin plastic LQFP (FPT-64P-M23)
MB96F623RBPMC-GSE2		
MB96F623RBPMC-GTE1		
MB96F623RBPMC1-GSE1		64-pin plastic LQFP (FPT-64P-M24)
MB96F623RBPMC1-GSE2		
MB96F623RBPMC1-GTE1		
MB96F625RBPMC-GSE1	Flash A (160.5KB)	64-pin plastic LQFP (FPT-64P-M23)
MB96F625RBPMC-GSE2		
MB96F625RBPMC-GTE1		
MB96F625RBPMC1-GSE1		64-pin plastic LQFP (FPT-64P-M24)
MB96F625RBPMC1-GSE2		
MB96F625RBPMC1-GTE1		

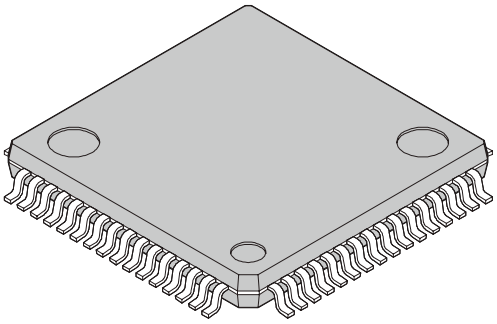
*: For details about package, see "PACKAGE DIMENSION".

MCU without CAN controller

Part number	Flash memory	Package*
MB96F622ABPMC-GSE1	Flash A (64.5KB)	64-pin plastic LQFP (FPT-64P-M23)
MB96F622ABPMC-GSE2		
MB96F622ABPMC-GTE1		
MB96F622ABPMC1-GSE1		64-pin plastic LQFP (FPT-64P-M24)
MB96F622ABPMC1-GSE2		
MB96F622ABPMC1-GTE1		
MB96F623ABPMC-GSE1	Flash A (96.5KB)	64-pin plastic LQFP (FPT-64P-M23)
MB96F623ABPMC-GSE2		
MB96F623ABPMC-GTE1		
MB96F623ABPMC1-GSE1		64-pin plastic LQFP (FPT-64P-M24)
MB96F623ABPMC1-GSE2		
MB96F623ABPMC1-GTE1		
MB96F625ABPMC-GSE1	Flash A (160.5KB)	64-pin plastic LQFP (FPT-64P-M23)
MB96F625ABPMC-GSE2		
MB96F625ABPMC-GTE1		
MB96F625ABPMC1-GSE1		64-pin plastic LQFP (FPT-64P-M24)
MB96F625ABPMC1-GSE2		
MB96F625ABPMC1-GTE1		

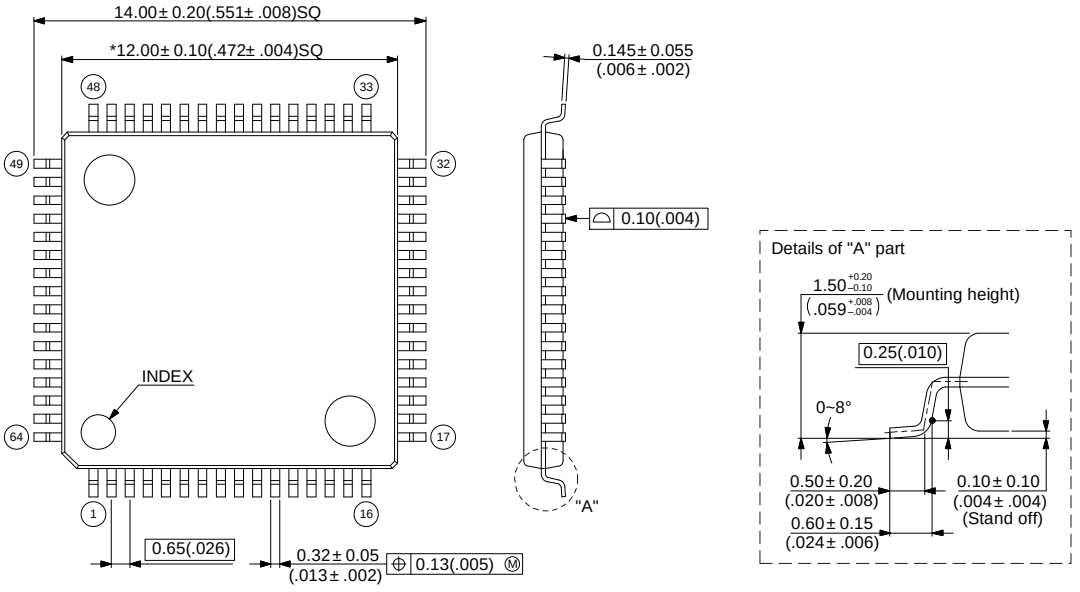
*: For details about package, see "PACKAGE DIMENSION".

17. Package Dimension

64-pin plastic LQFP		
	Lead pitch	0.65 mm
	Package width × package length	12.0 × 12.0 mm
	Lead shape	Gullwing
	Sealing method	Plastic mold
	Mounting height	1.70 mm MAX
	Weight	0.47 g
(FPT-64P-M23)	Code (Reference)	P-LQFP64-12 × 12-0.65

64-pin plastic LQFP
(FPT-64P-M23)

Note 1) * : These dimensions do not include resin protrusion.
Note 2) Pins width and pins thickness include plating thickness.
Note 3) Pins width do not include tie bar cutting remainder.



Dimensions in mm (inches).
Note: The values in parentheses are reference values